

OMB No. 0651-0011


## INFORMATION DISCLOSURE CITATION

Atty. Docket No. 09304.0004-00000	Appln. No. 09/806,704
Applicant PALME et al.	
Filing Date 06/27/2001	Group: 2878

U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS					
Examiner Initials	Cite No. <sup>1</sup>	Document Number	Issue or Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
SY	A	2,922,331	Jan. 26, 1960	Fastie	
SY	B	3,917,407	Nov. 4, 1975	Newstead	
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Note: Copies of the U.S. Patent Documents are not Required in IDS filed after October 21, 2004

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation <sup>4</sup>
		Country Code <sup>2</sup> Number <sup>3</sup> Kind Code <sup>4</sup> (if known)				
SY	J	EP 0 855 811 A2	Jul. 29, 1998	GPT Limited		
SY	K	EP 0 859 249 A1	Aug. 19, 1998	Photonetics		
SY	L	EP 1 135 707 B1	Sep. 26, 2001	Tektronix Munich GmbH		No
SY	M	DE 2 437 253	May 15, 1975	Jenoptik Jena GmbH		No
SY	N	DE 19 816 612 A1	Oct. 21, 1999	Bandemer et al.		No

Examiner 	Date Considered 1/5/05
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	
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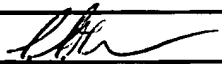


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## INFORMATION DISCLOSURE CITATION

Atty. Docket No. 09394-0004-00000	Appln. No. 09/806,704
Applicant PALME et al.	
Filing Date 06/27/2001	Group: 2878

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation <sup>8</sup>
SY	O	AMRANI A et al.: "Degradation surveillance module for optical transport networks," Conference Proceedings. LEOS' 98. 11 <sup>th</sup> Annual Meeting. IEEE Lasers and Electro-Optics Society 1998 Annual Meeting (CAT. No. 98CH36243), Conference Proceedings. LEOS'98. 11 <sup>th</sup> Annual Meeting. IEEE Lasers and Electro-Optics Society 1998 Annual Meeting, Or, December 1, 1998, pp. 289-290, Vol. 1, Piscataway, NJ, USA IEEE, USA ISBN: 0-7803-4947-4	
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SY	Q	ASAHI K. et al. "Optical Performance Monitor Built into EDFA Repeaters for WDM Networks," OFC '98, Optical Fiber Communication Conference and Exhibit, Technical Digest, Conference Edition. 1998 OSA Technol Digest Series Vol. 2 (IEEE CAT No.98CH36177), OFC '98 Optical Fiber Communication Conference and Exhibit. pp. 318-319, XP002134593 1998, Washington, DC, USA, Opt. Soc. America, USA ISBN: 1-55752-521-8	
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SY	T	FASTIE, "Ebert Spectrometer Reflections," <i>Physics Today</i> , pp. 37-43 (January 1991).	
SY	U	FASTIE, "A Small Plane Grating Monochromator," <i>Journal of the Optical Society of America</i> , Vol. 42, No. 9, pp. 641-647 (September 1952).	
SY	V	Response to Examination report filed in corresponding European Application No. 99 950 610.8 on August 7, 2002.	Yes
SY	W	"Analytical Emission Spectroscopy" edited by E.L. GROVE, Section 4 by R.M. Barnes and R.F. Jarrell "Gratings and Grating Instruments," New York, M. Dekker, pp. 255-309 (1971).	

Examiner 	Date Considered 1/5/05
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